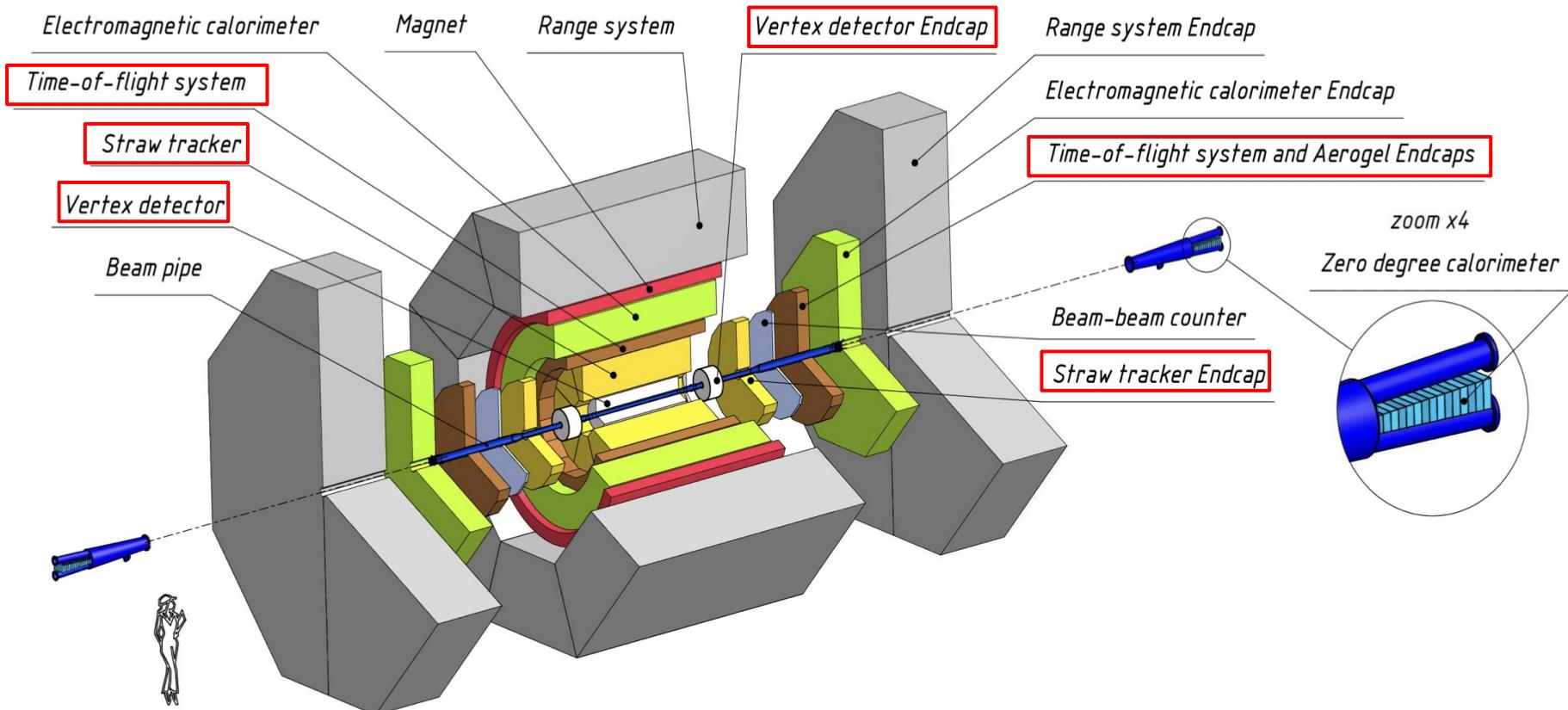


dE/dx and TOF performance at SPD

Artem Ivanov, Ruslan Akhunzyanov
JINR, Dubna

SPD Collaboration Meeting
6.10.2022

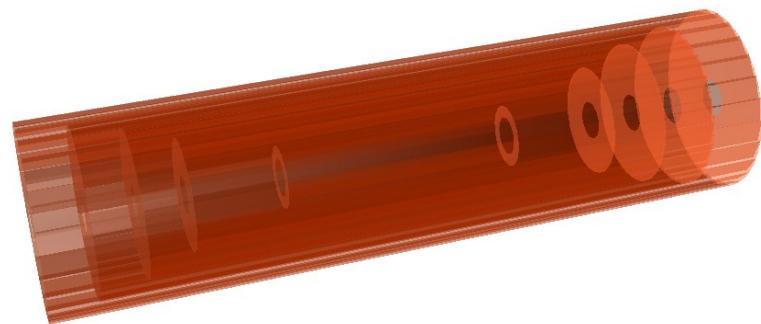
Particle identification in SPD



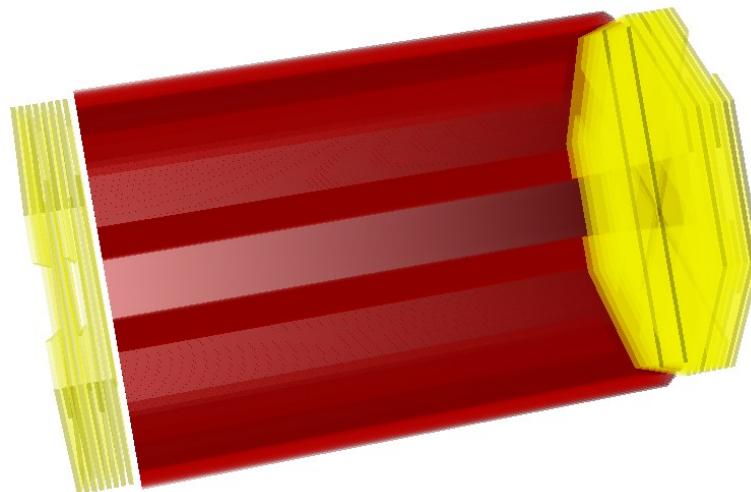
Not discussed in this talk: particle identification via **RS** (muons) and **ECAL** (electron and photon)

Particle identification in SpdRoot

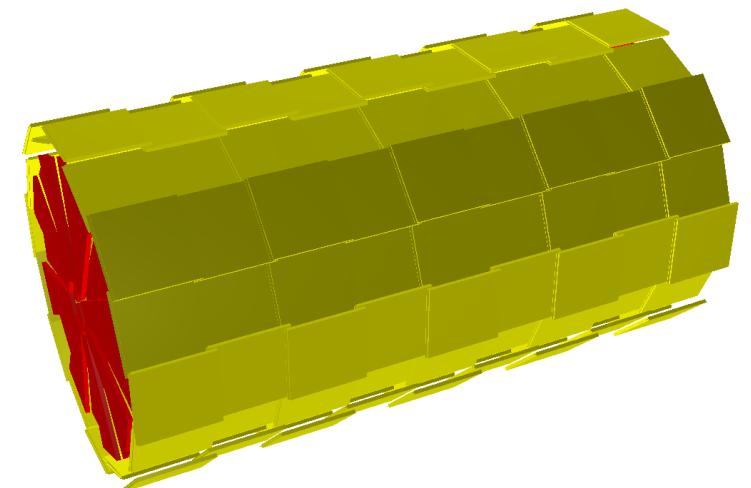
VD (5 layers DSSD)
(TDR→3 layers)



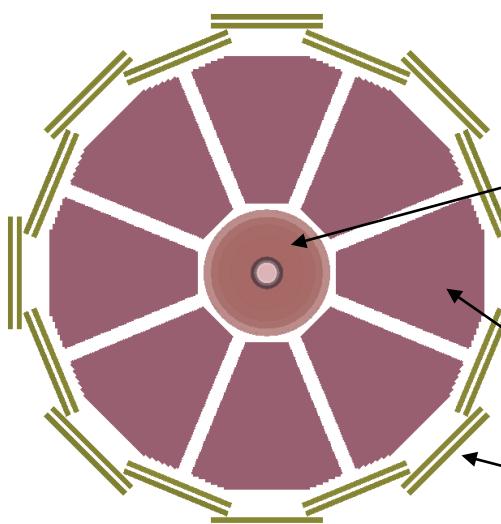
Straw



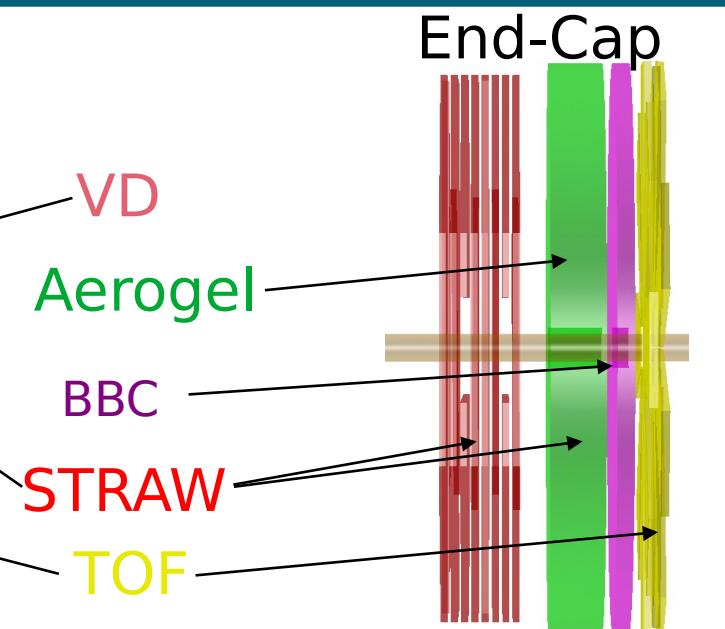
TOF



Barrel



End-Cap

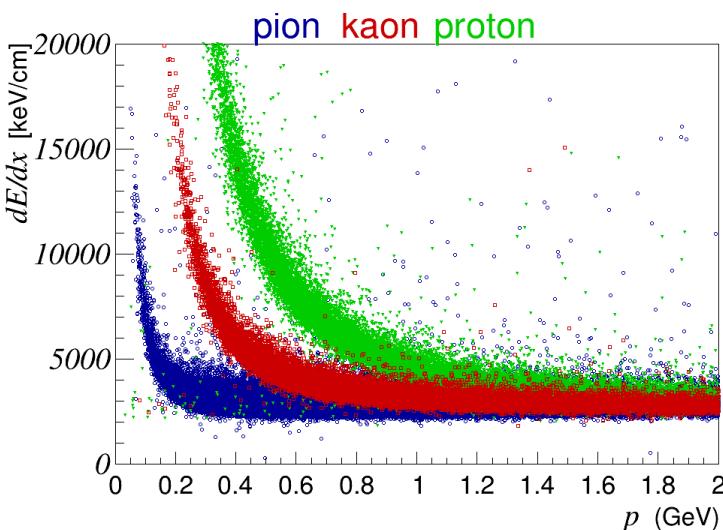


Aerogel

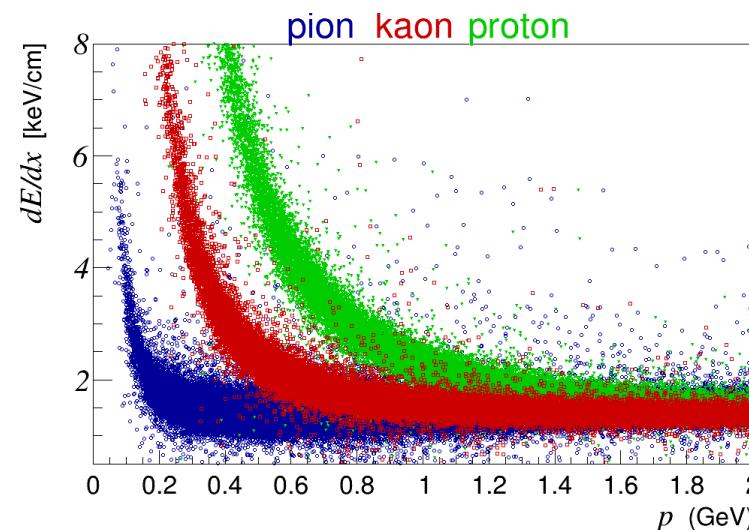


Particle identification in SpdRoot

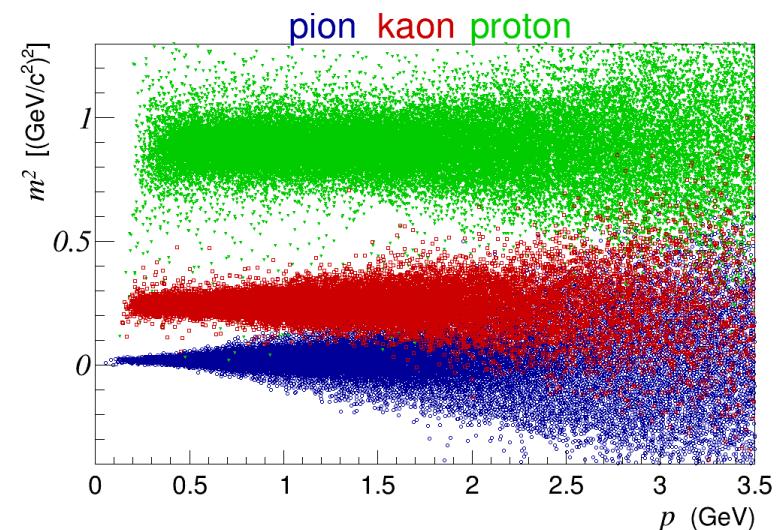
VD



Straw

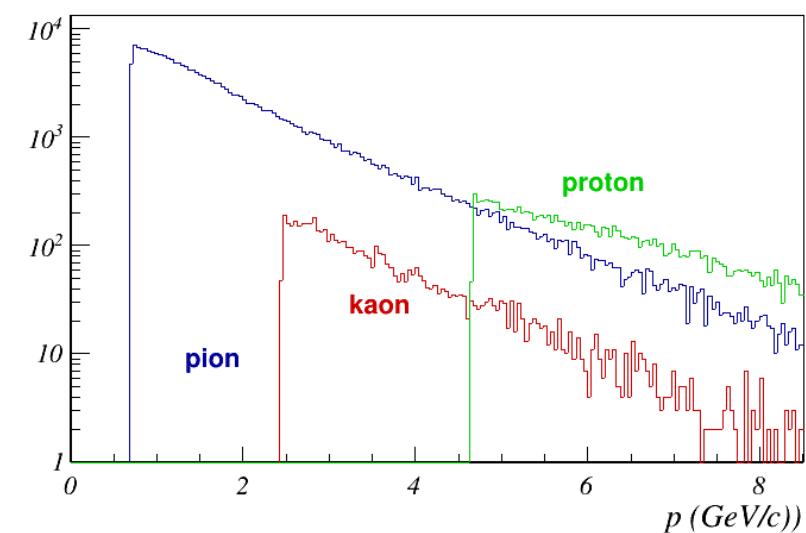


TOF



Detector	Signal
VD	ionization energy loss (dE/dx)
Straw	ionization energy loss (dE/dx)
TOF	time of flight
Aerogel	Cerenkov radiation

Aerogel



Typical PID approaches

For a detector with a Gaussian response

Observed signal from a detector

PID discrimination variable $\rightarrow n_{\sigma_\alpha^i} = \frac{S_\alpha - \hat{S}(H_i)_\alpha}{\sigma_\alpha^i}$

What we expect for a given m hypothesis

$\alpha = VD, STRAW, TOF \dots$

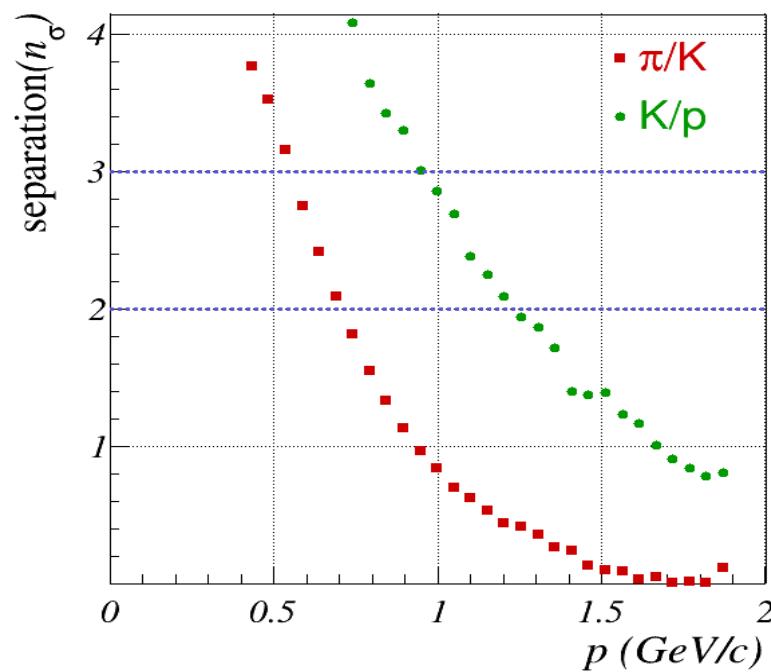
$i = e, \pi, K, p \dots$

detector resolution

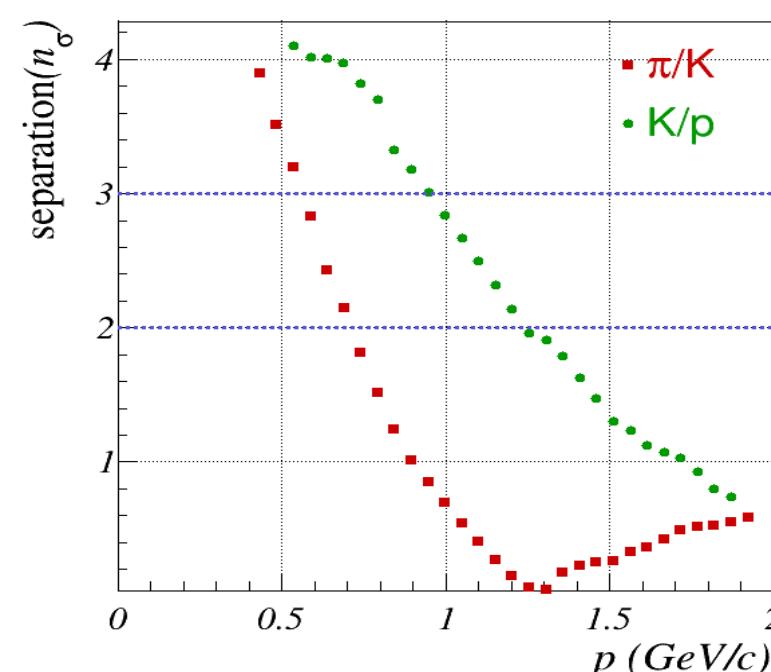
The diagram illustrates the formula for the PID discrimination variable. It shows an observed signal from a detector being compared to a hypothesis expectation. The difference is normalized by the detector's resolution, which is labeled as σ_α^i . Arrows point from the text labels to the corresponding parts of the equation.

Separation power

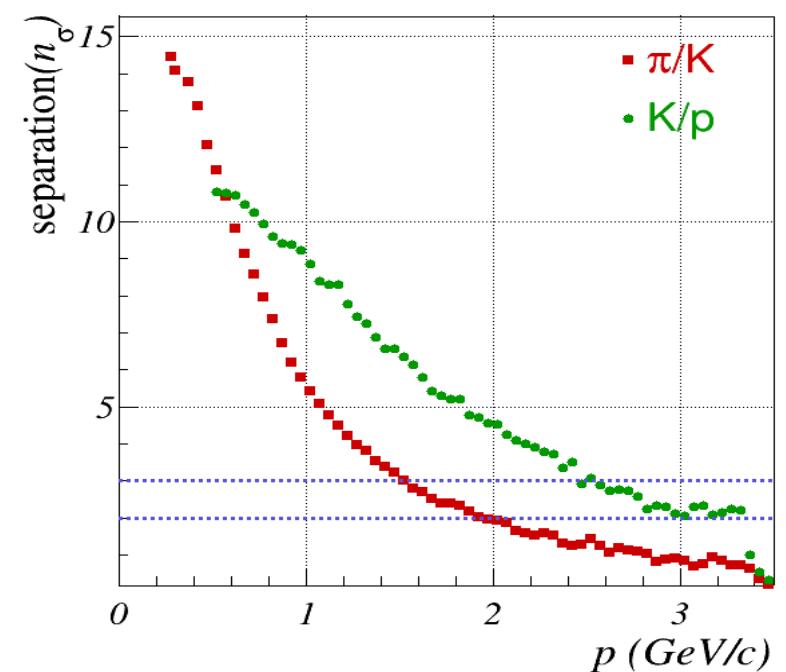
VD



Straw

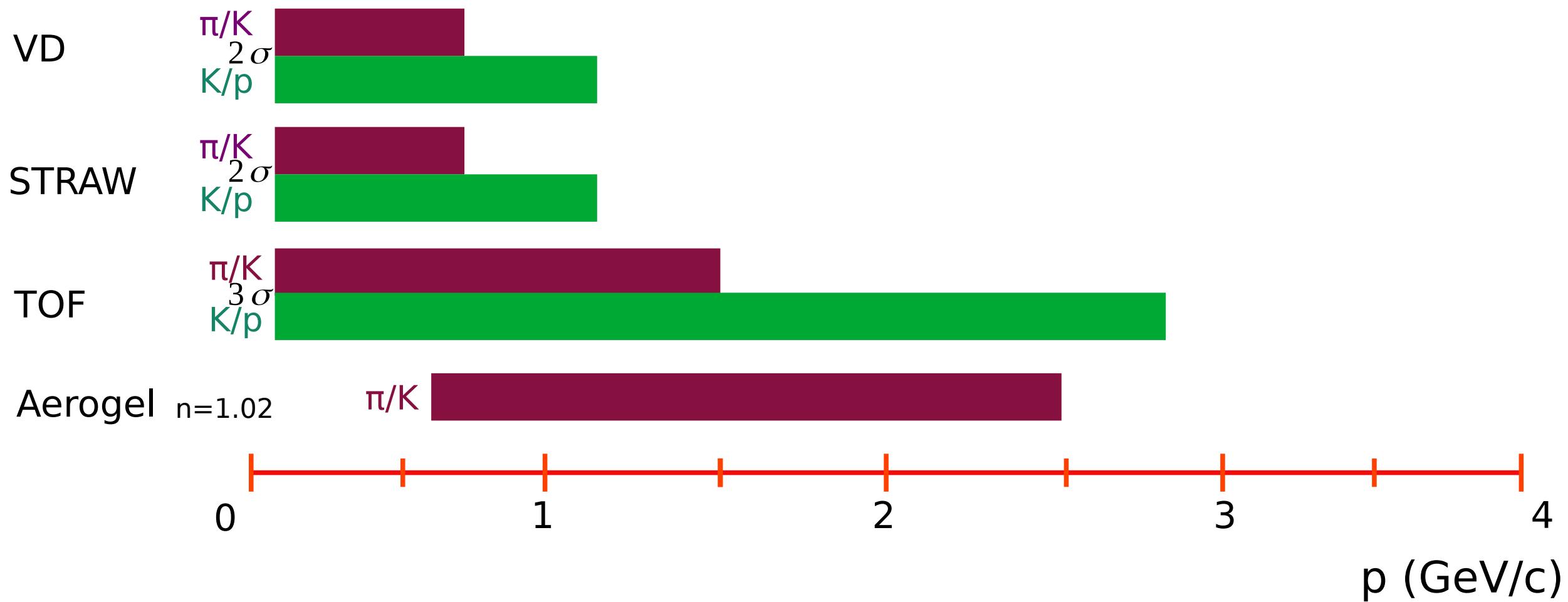


TOF

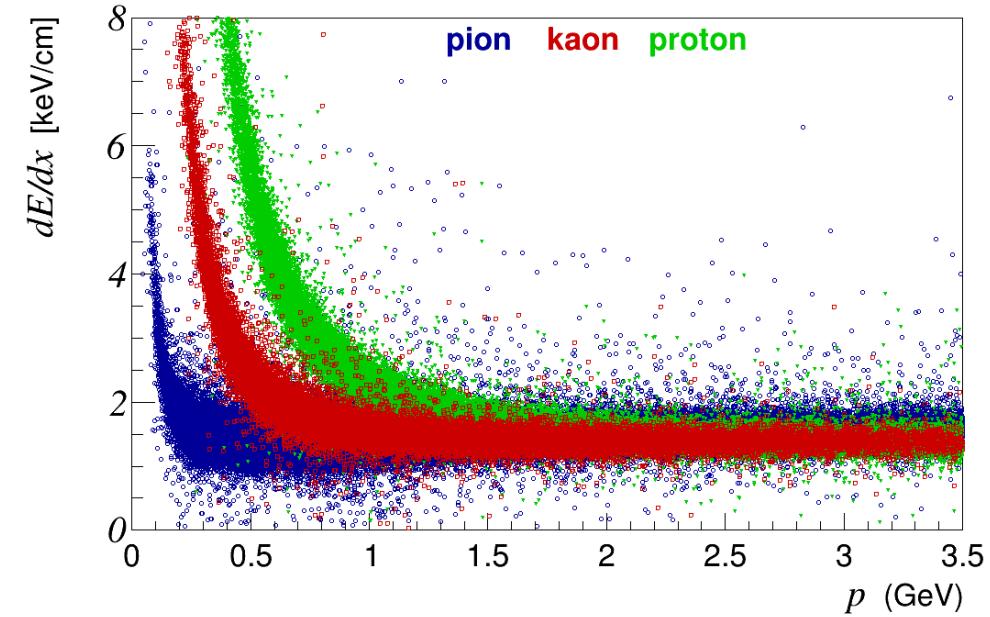
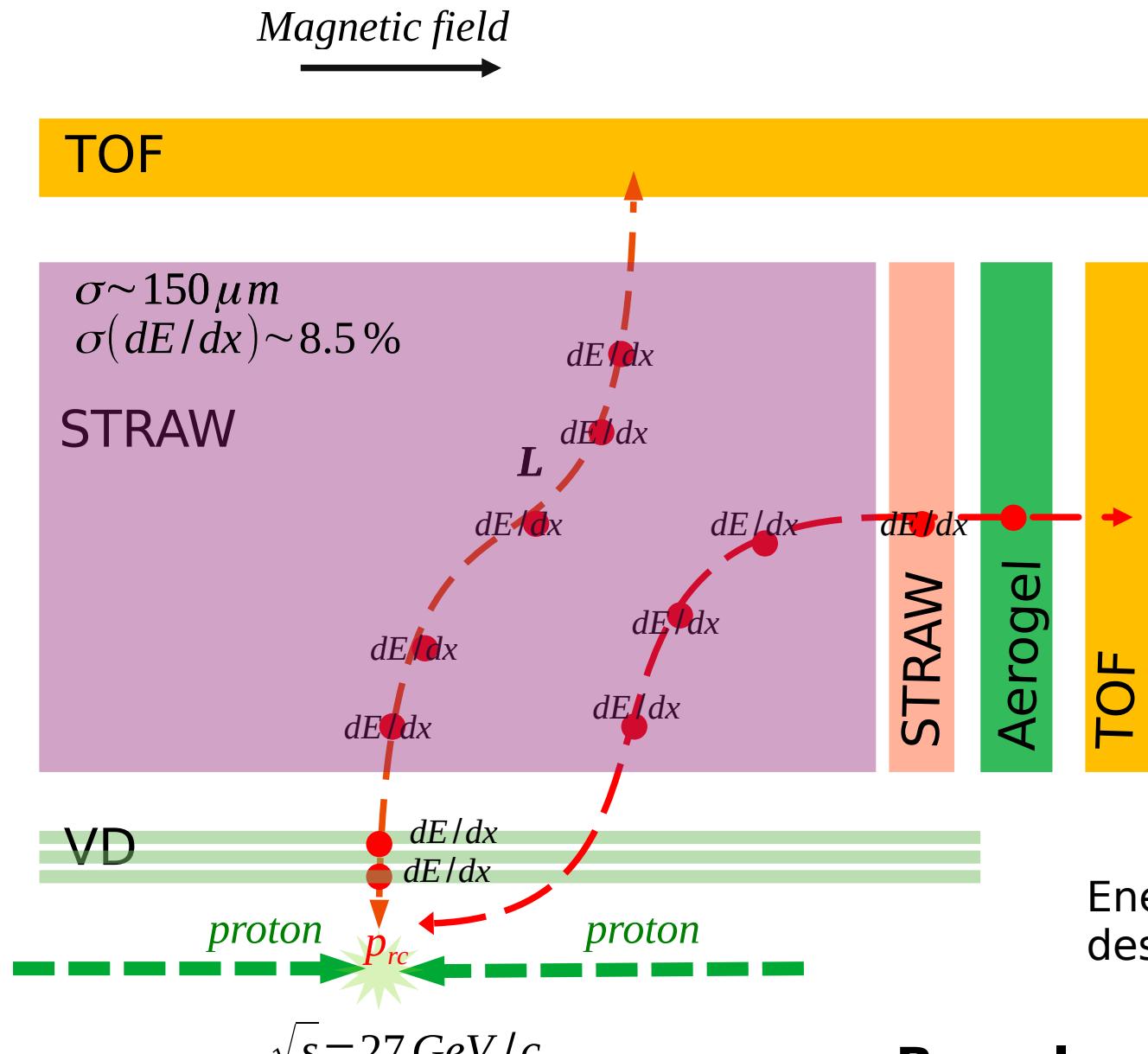


$$separation = \frac{\mu_i - \mu_j}{\sqrt{\sigma_i^2 + \sigma_j^2}}$$

Particle identification in SPD



Straw Tracker



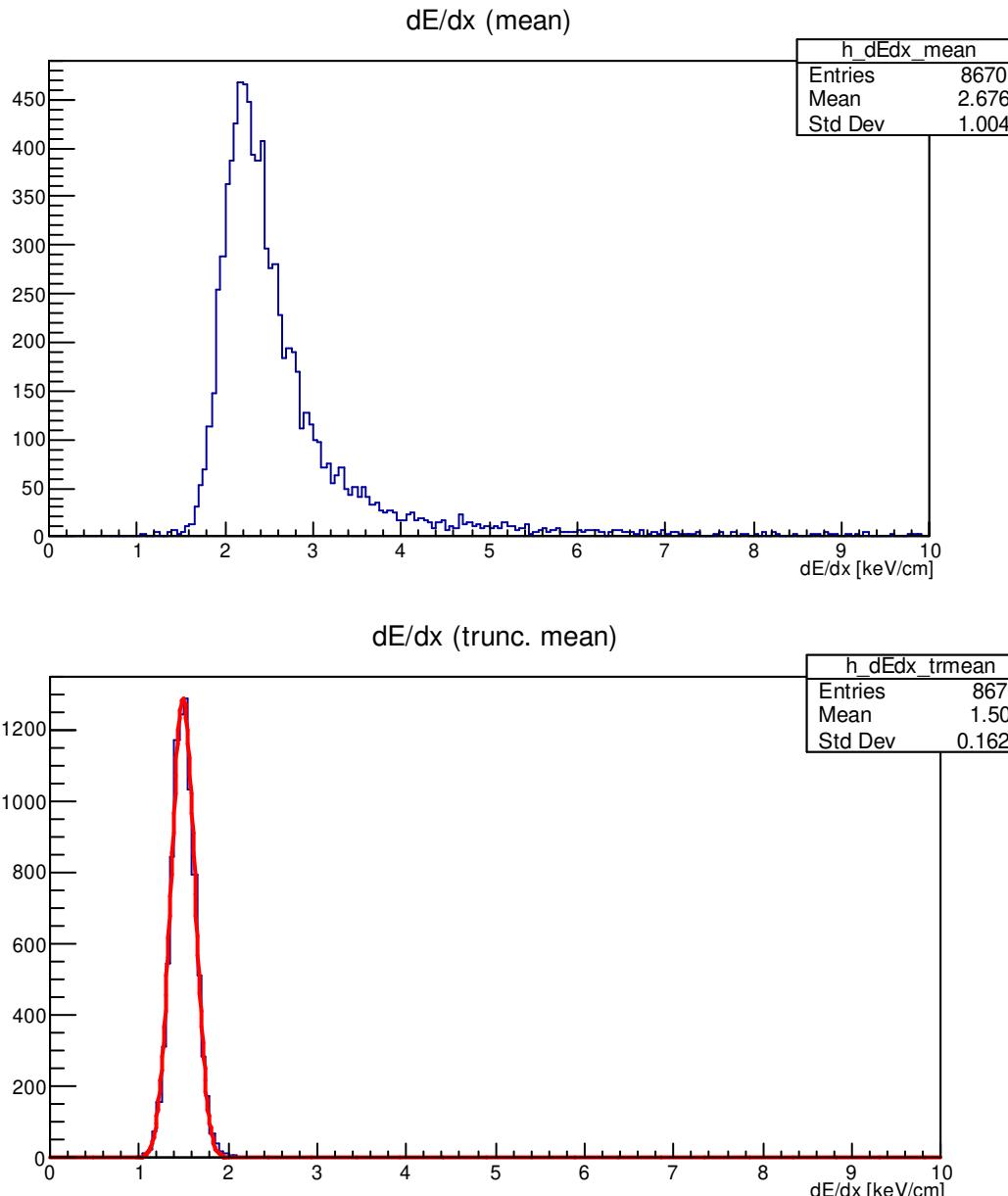
Each track crosses several straw tubes.
In simplest case, we calculate mean value of dE/dx for each track

Energy loss per unit path length (dE/dx) is described by the Bethe-Bloch formula

Barrel: 29 double layers
End-Cap: 8 double layers

Truncated mean method for STRAW

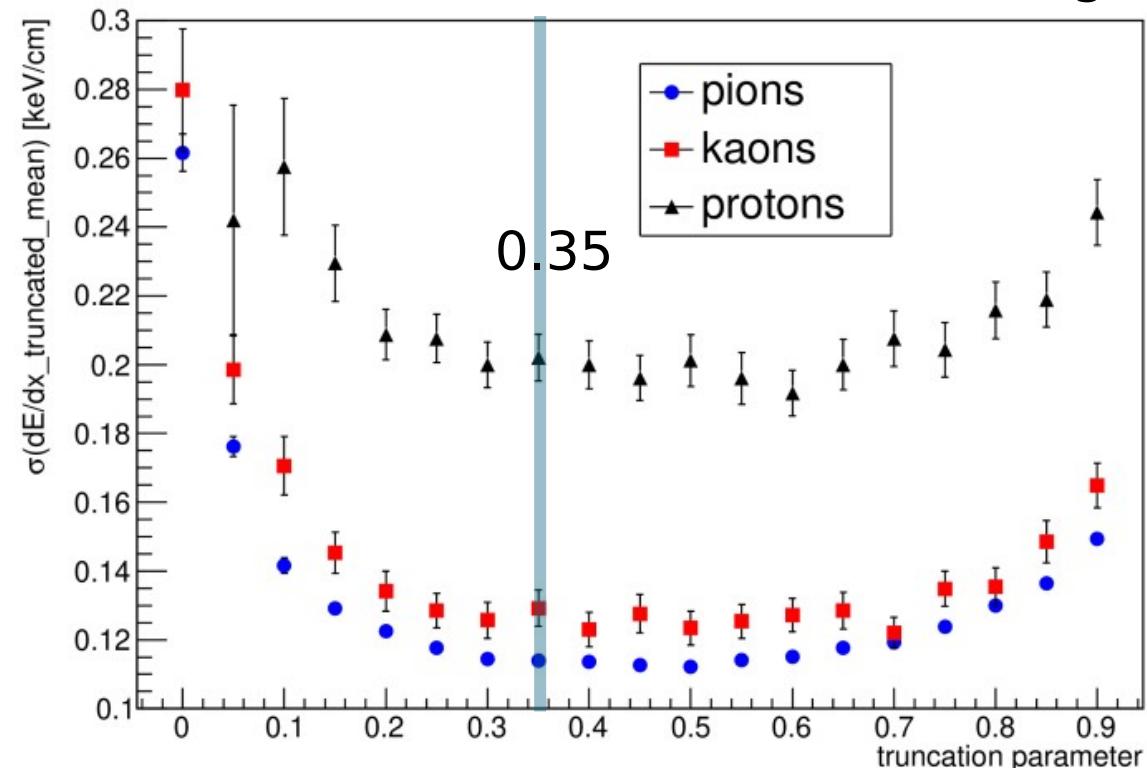
Truncated mean is used to remove fluctuations due to the tail towards higher deposits (“Landau-like”)



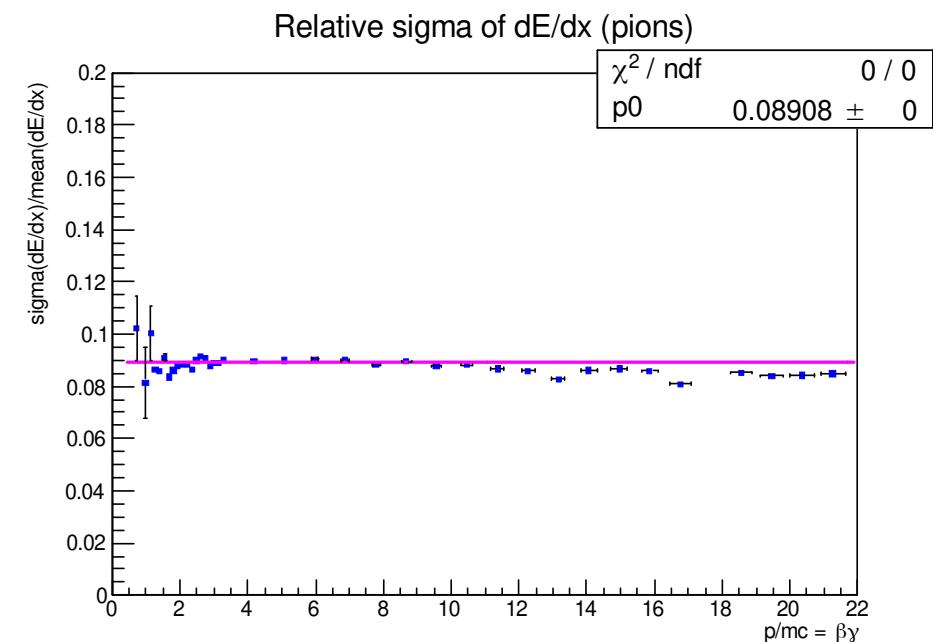
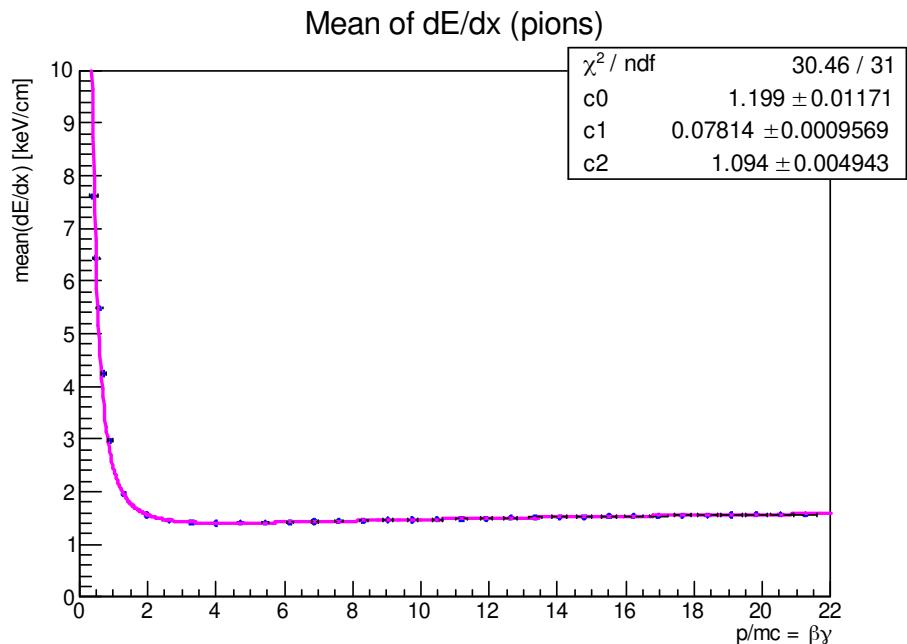
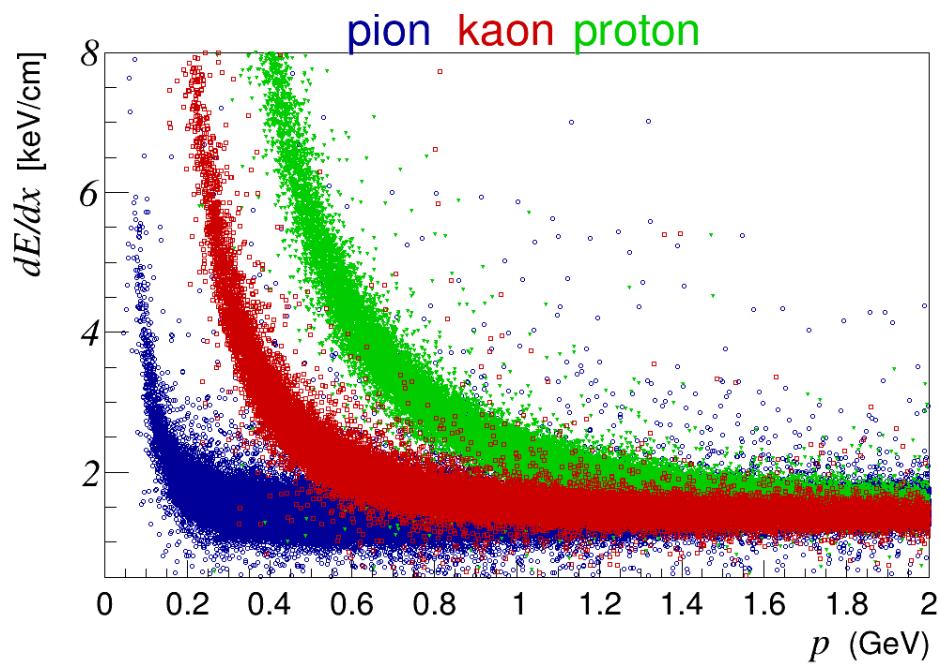
Example shown here for pions:

- $p_0 = 0.312 \text{ GeV}/c$
- truncation parameter 0.35.

Truncated mean dE/dx distribution sigma



How to parametrize pions in STRAW



Parameterization of truncated mean dE/dx distribution

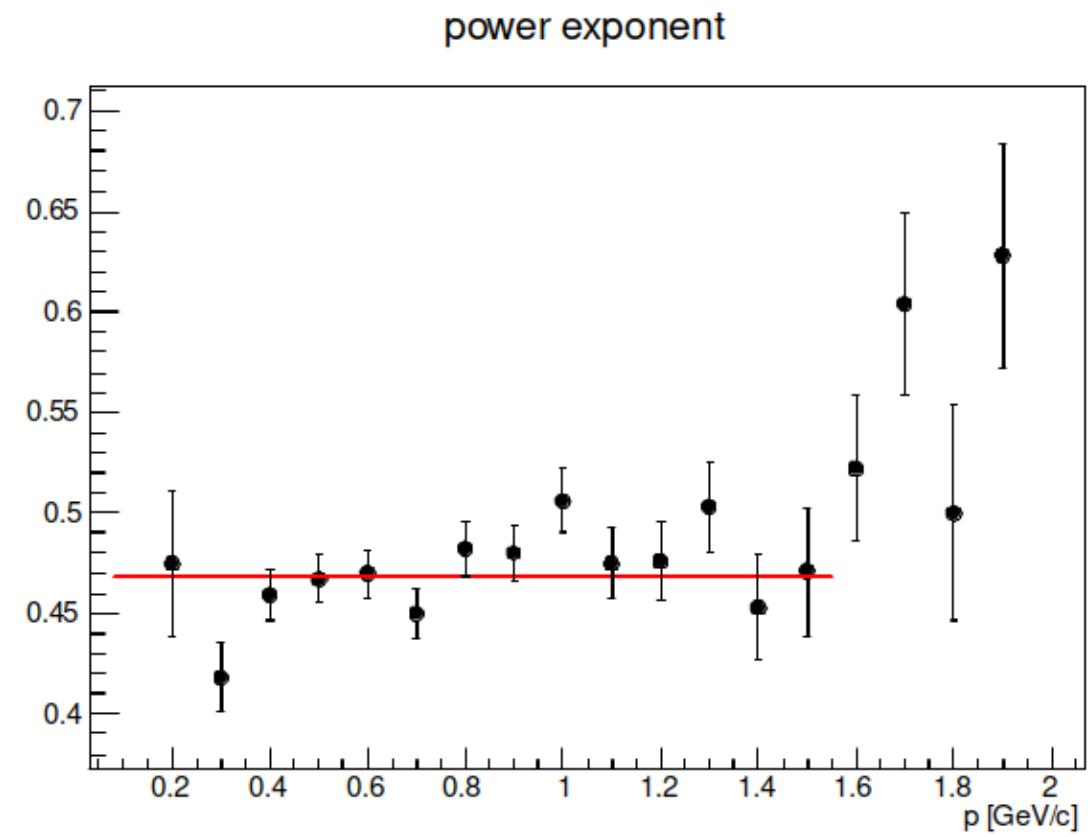
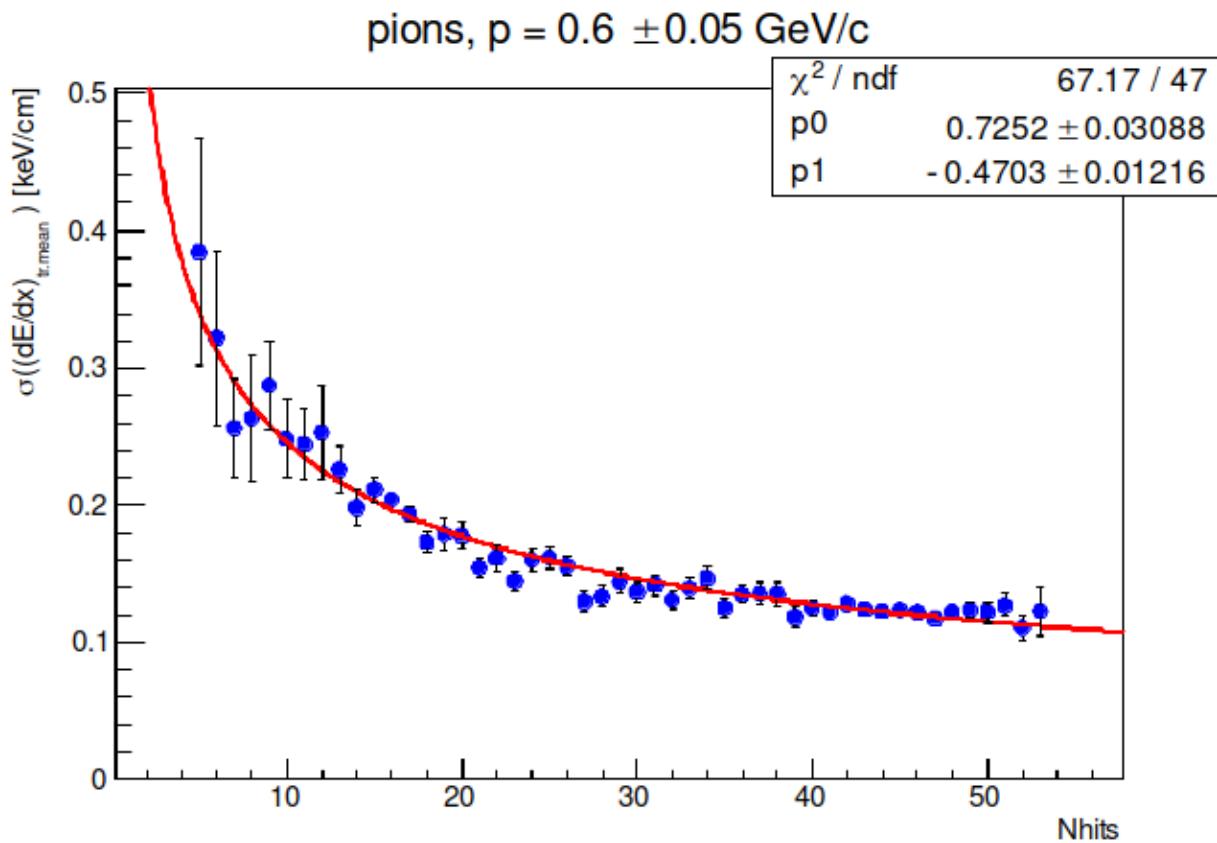
$$\text{mean} = \frac{c_0}{\beta^2} + \frac{c_1}{\beta^2} \ln(\beta\gamma) - (c_0 - c_2) \left(1 + \frac{\ln(\beta^2)}{\beta^2}\right)$$

$$\beta\gamma = p/m, \quad \beta^2 = \frac{(p/m)^2}{(p/m)^2 + 1}$$

$$\sigma = R \cdot \text{mean}$$

Dependence of $\sigma((dE/dx)_{\text{trunc.mean}})$ on number of hits

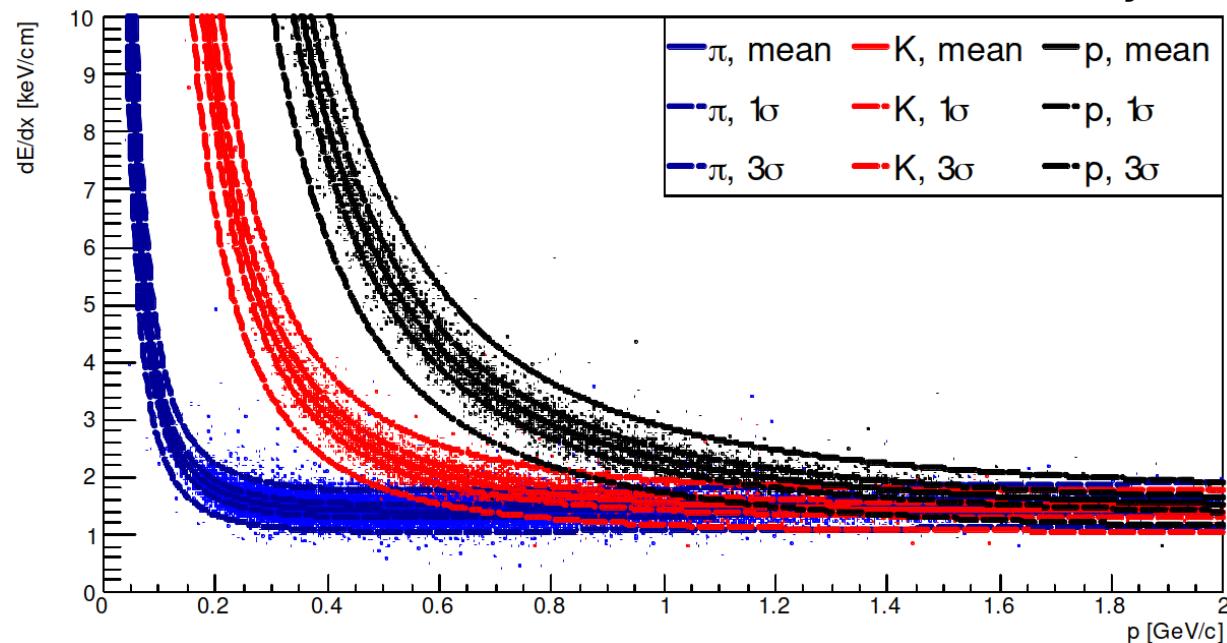
- Naive expectation: $\sigma \sim 1/\sqrt{N_{\text{hits}}}$



Parametrization dEdx vs p for STRAW

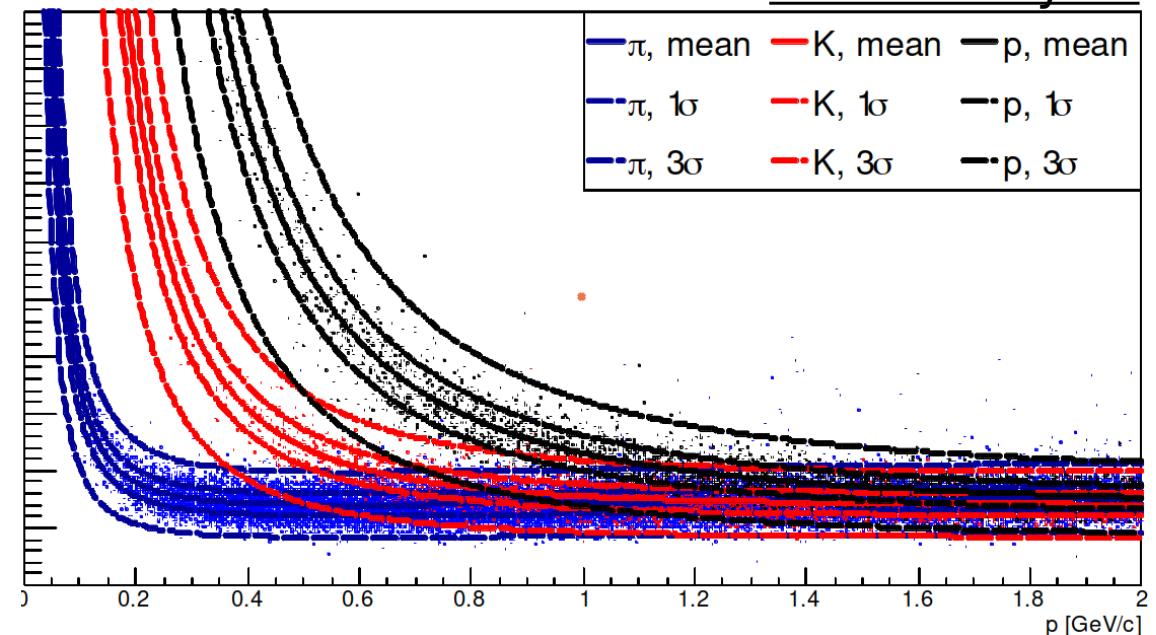
Barrel

29 double layers



End-Cap

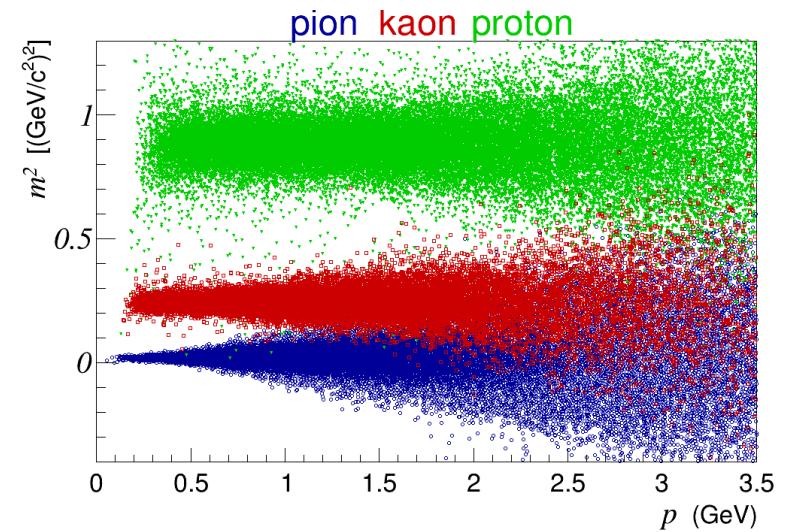
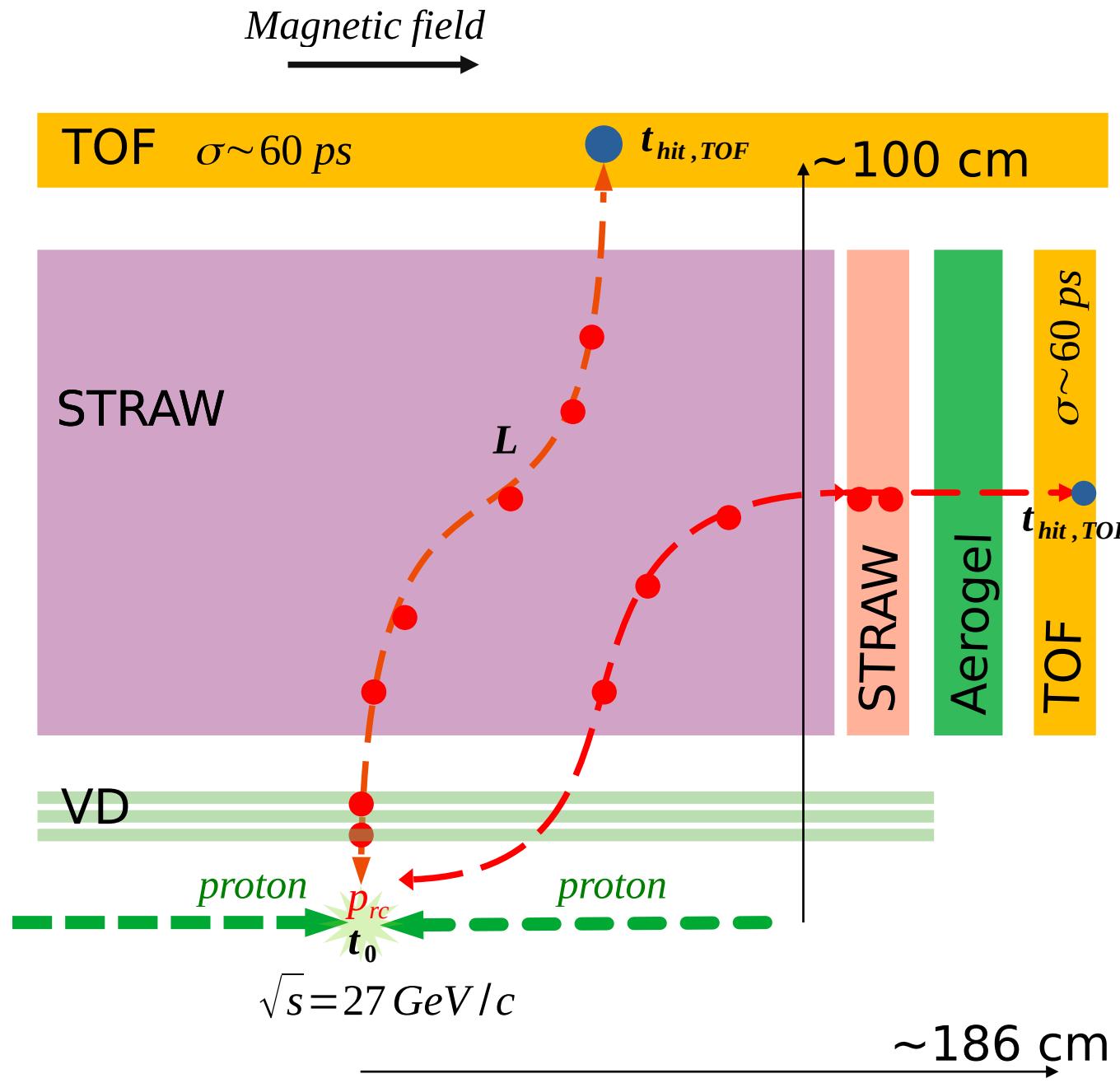
8 double layers



End-Cap: pions separable from kaons up to ~ 0.45 GeV/c, from protons up to ~ 0.85 GeV/c

Barrel: pions separable from kaons up to ~ 0.6 GeV/c, from protons up to ~ 1.1 GeV/c

Time of Flight system



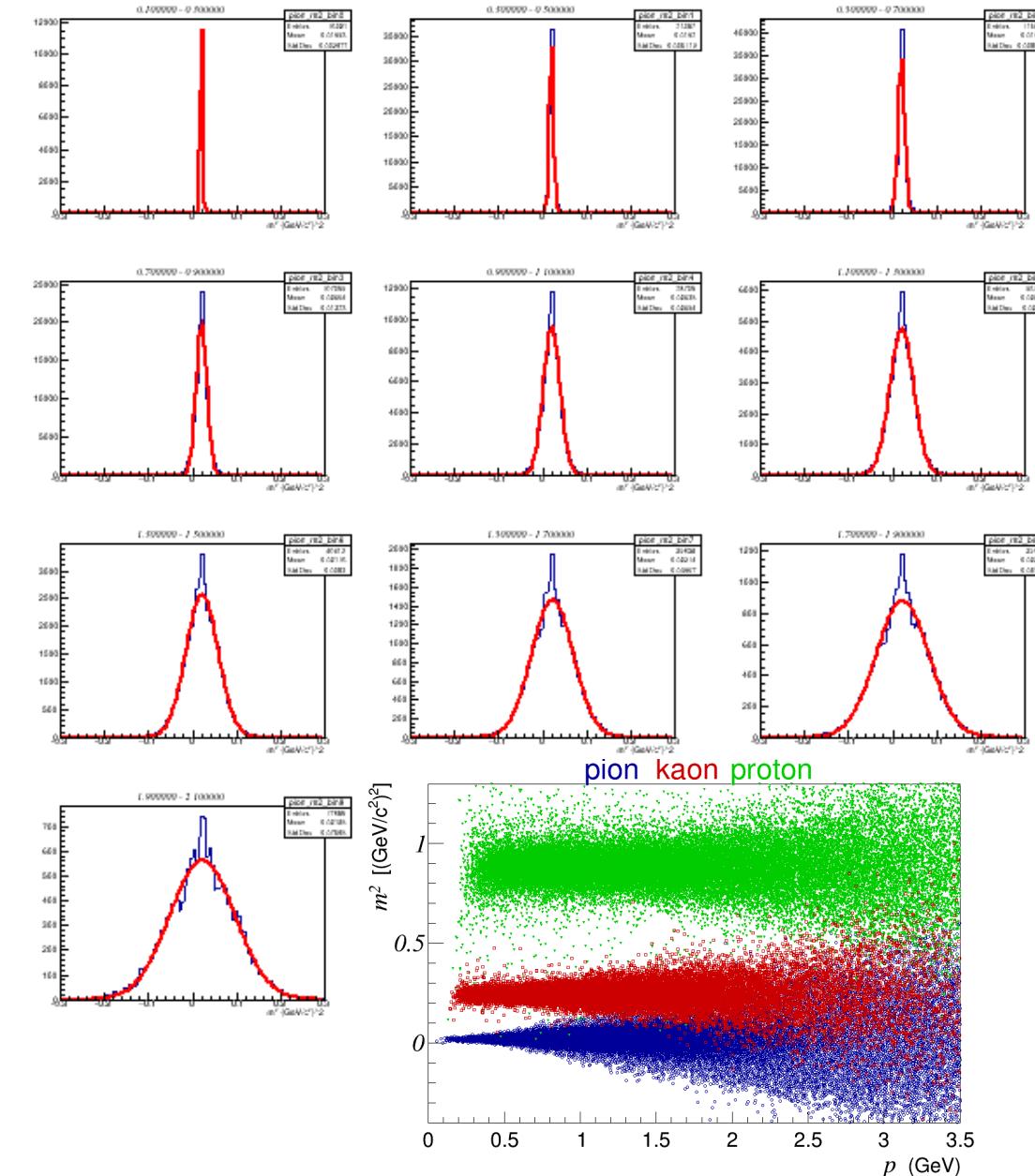
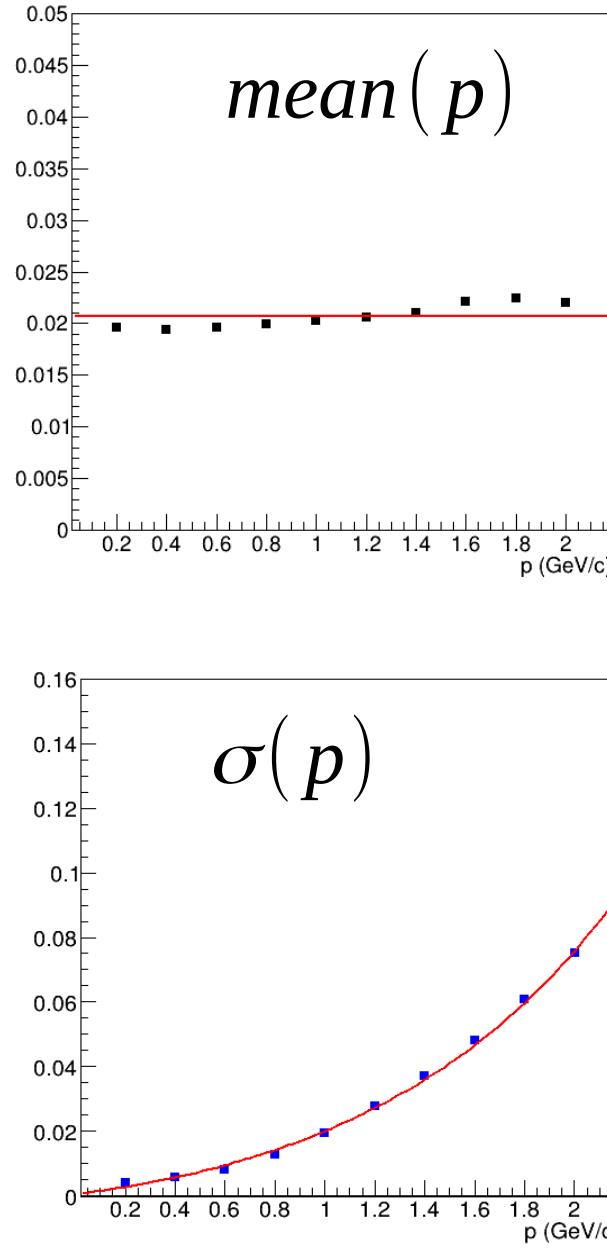
$$m^2 = \frac{p^2}{c^2} \left[\frac{t_{\text{TOF}}^2 c^2}{L^2} - 1 \right]$$

$$\sigma_{m^2}^2 = 4m^4 \left(\frac{\sigma_p}{p} \right)^2 + 4E^4 \left(\frac{\sigma_t}{t} \right)^2 + 4E^4 \left(\frac{\sigma_L}{L} \right)^2$$

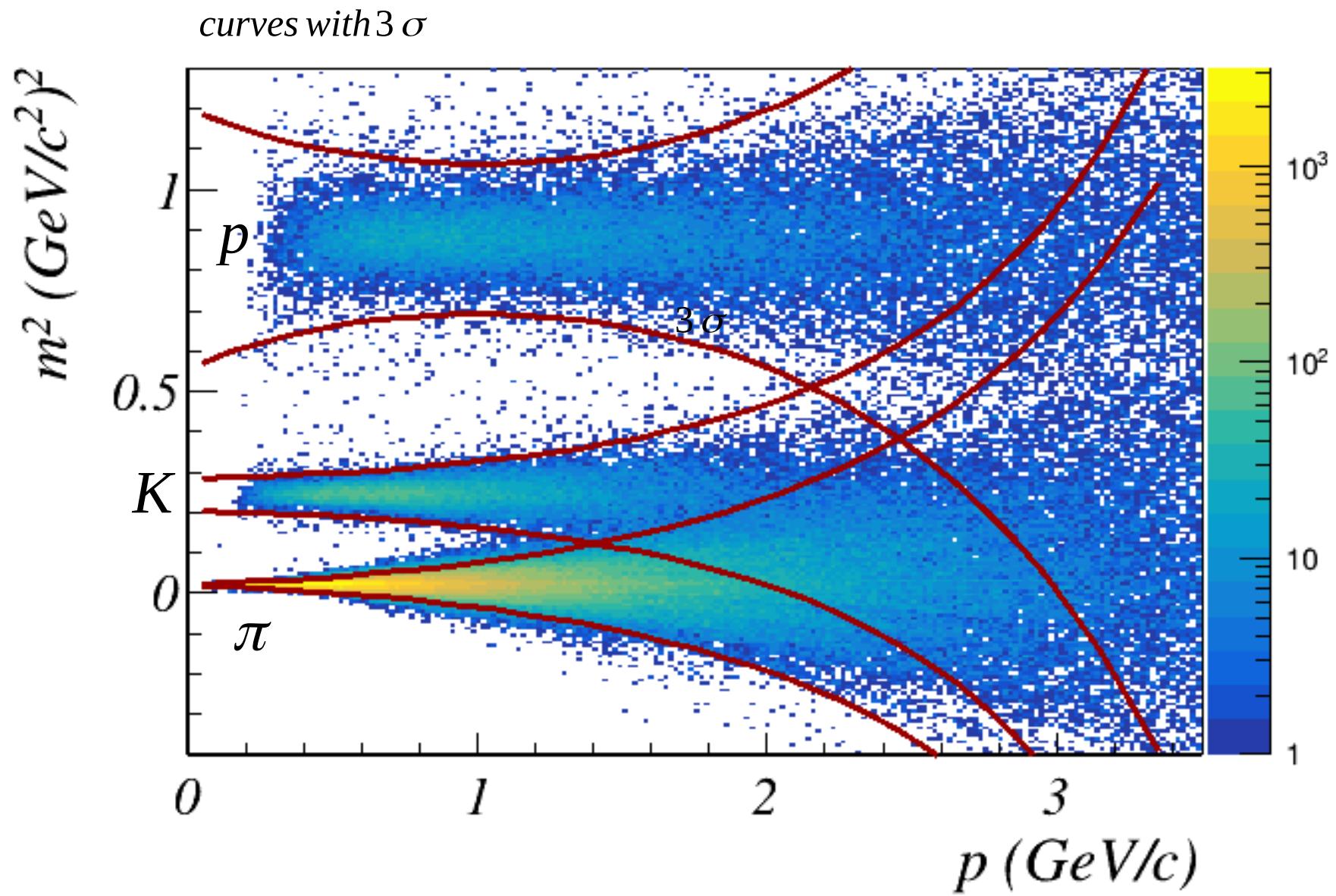
from reconstruction $\sigma \sim 150 \mu\text{m}$ $\sigma_{\text{TOF}} = 60 \text{ ps}$ at the moment fixed

13

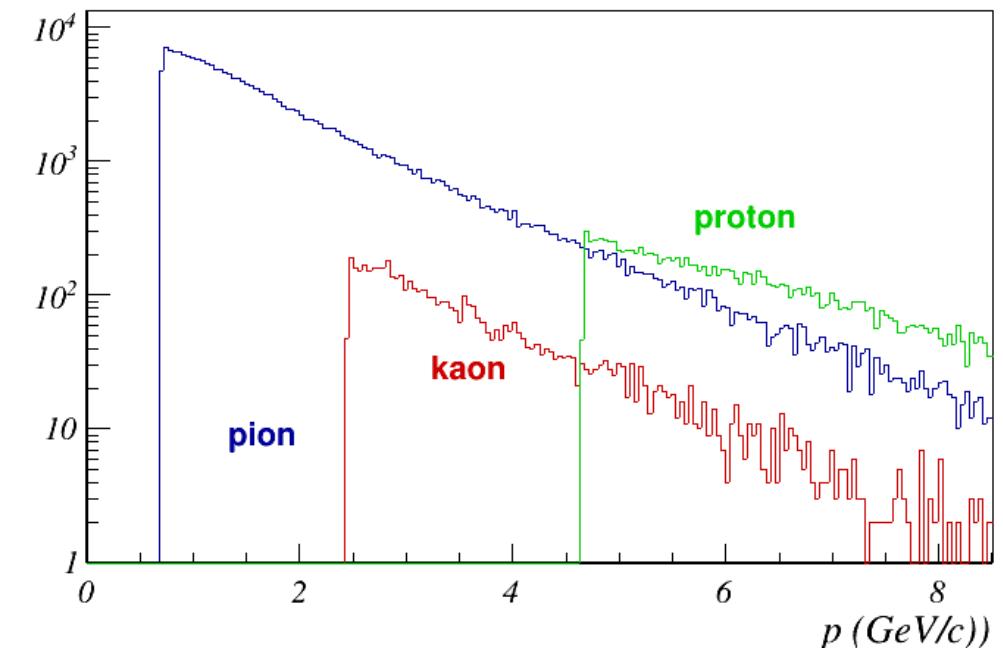
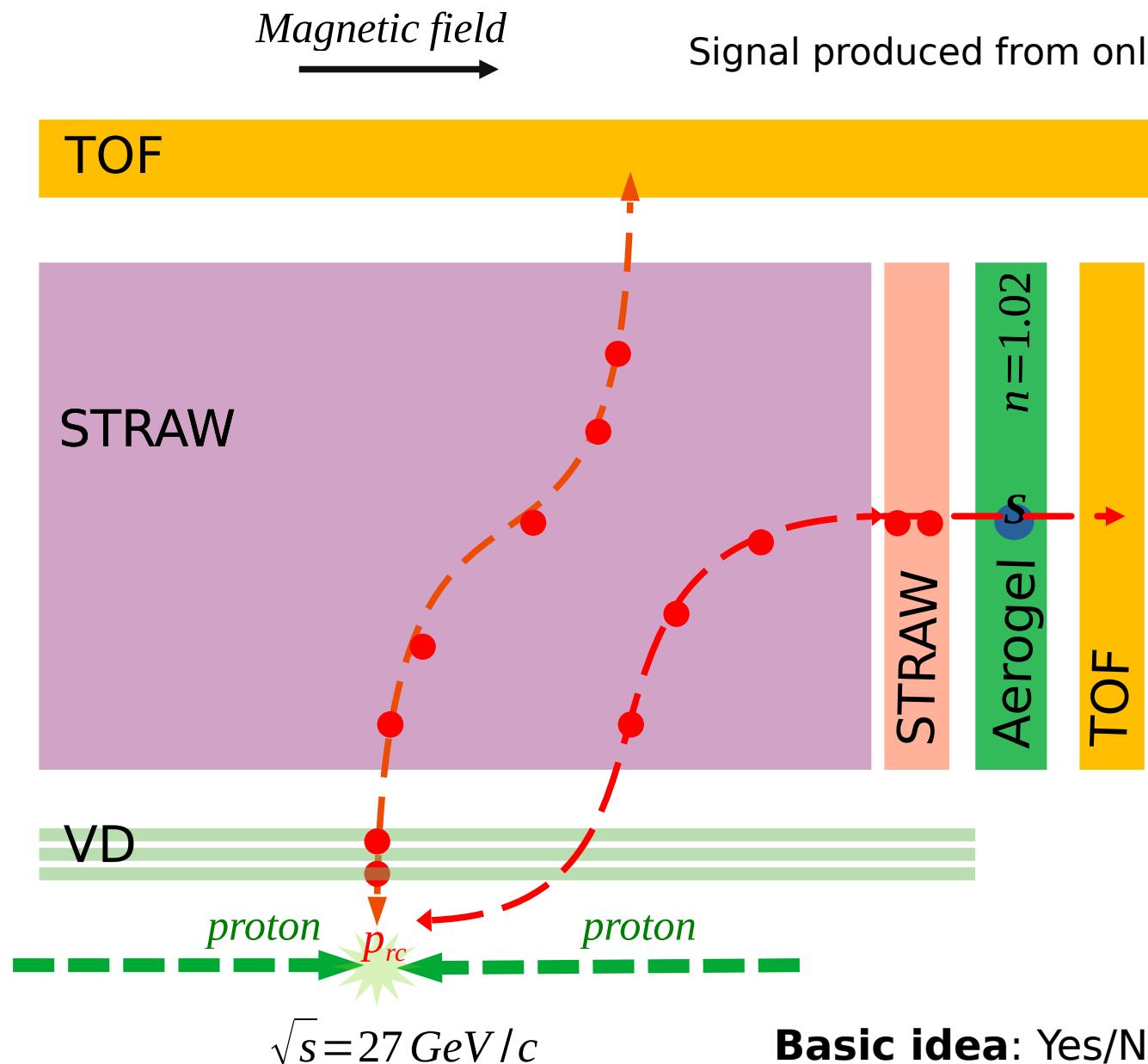
How to parametrize pions in TOF



Parametrization m^2 vs p for TOF



Threshold Aerogel counters

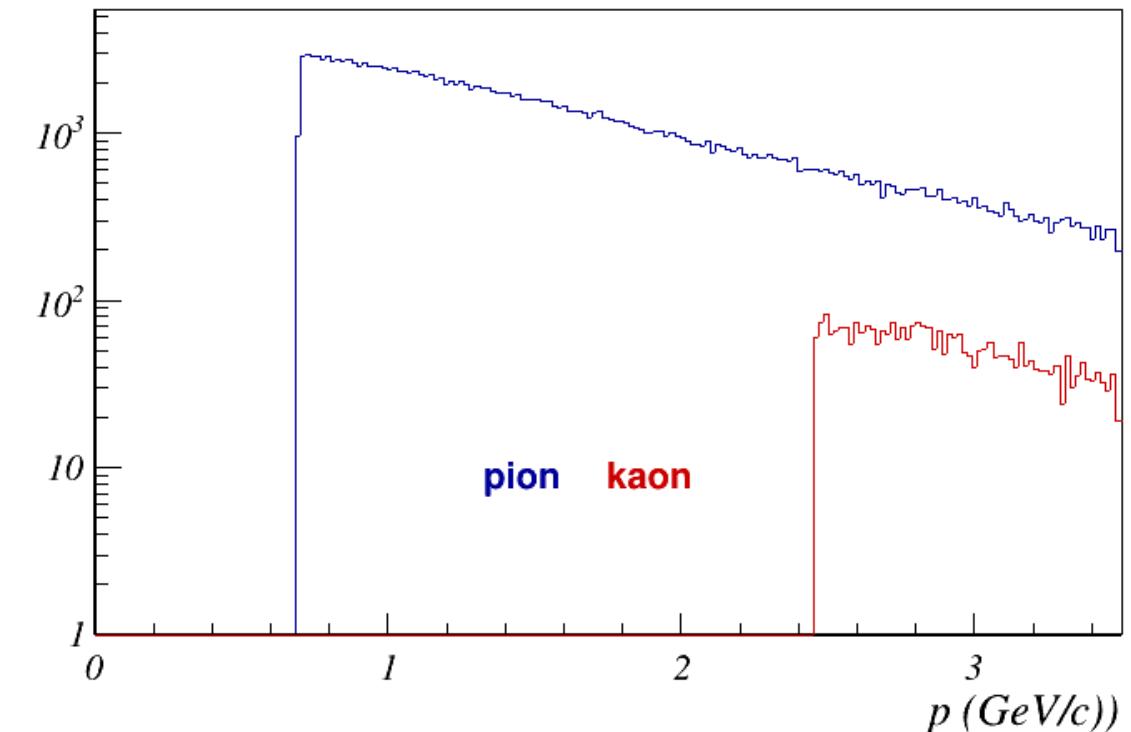
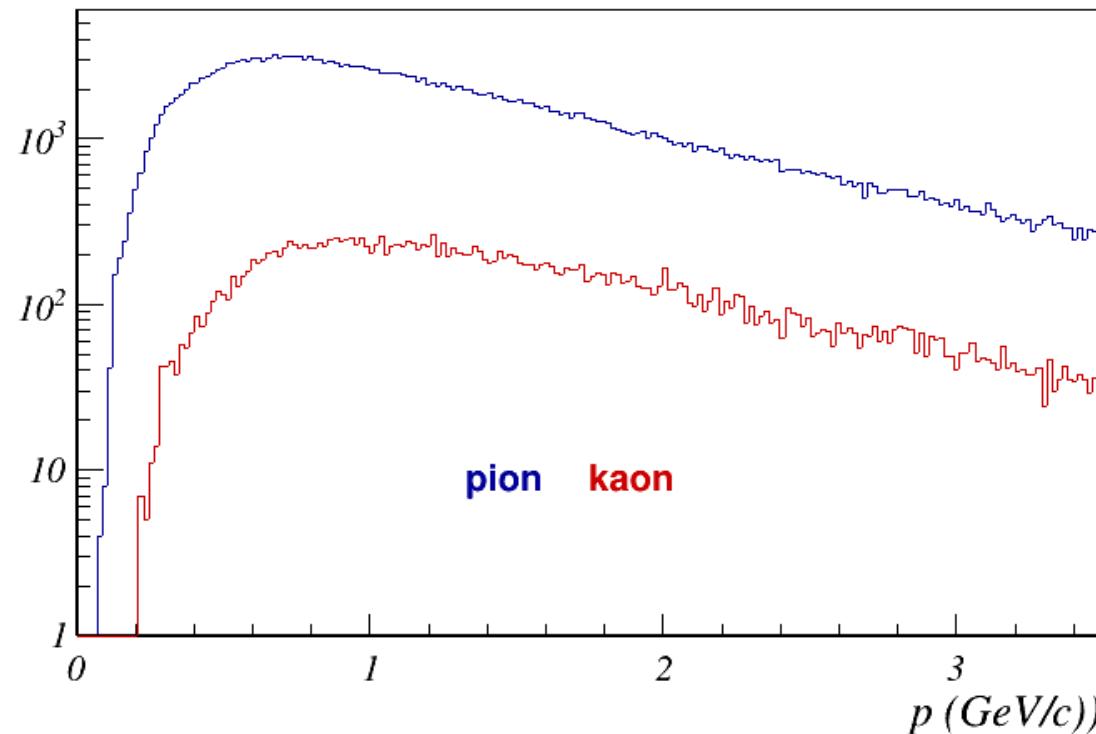


$$p_{th} = \frac{m}{\sqrt{n^2 - 1}}$$

Basic idea: Yes/No decision, on the existence of the particle type.
For this, count the number of photoelectrons detected

Threshold Aerogel counters

pion/kaon separation



$n=1.02$

	electron	muon	pion	kaon	proton
P_{th} (GeV/c)	0.0025	0.52	0.69	2.45	4.66

$$p_{th} = \frac{m}{\sqrt{n^2 - 1}}$$

PID methods

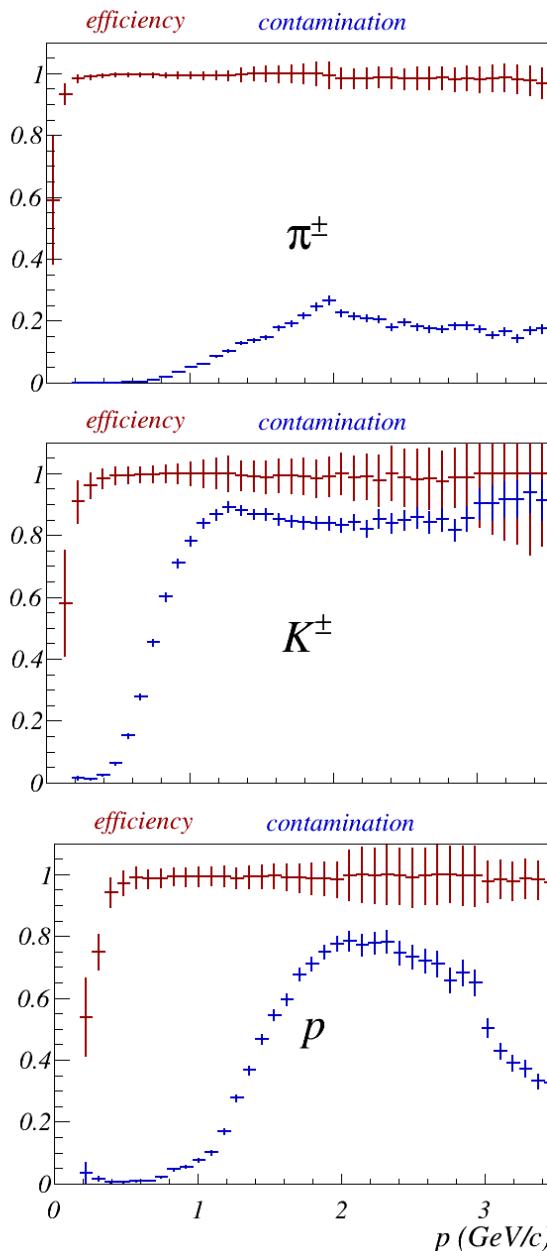
1. Define a cut on $n\sigma < k$, $k=1,2,3$ in single detector analysis
2. Define a multiple-cuts on $n\sigma$ for several detectors
3. Define a cut on a combined- $n\sigma$ variable

$$n \sigma_{comb} = \sqrt{n \sigma_{VD}^2 + n \sigma_{STRAW}^2 + n \sigma_{TOF}^2 \dots}$$

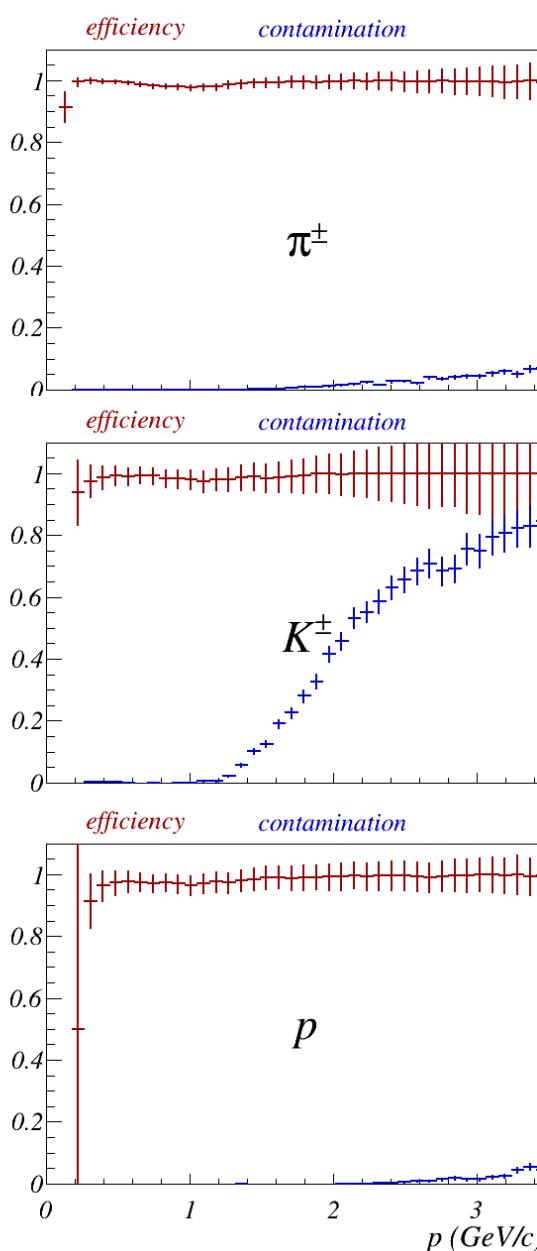
4. The Bayesian approach:
combine information from different PID detectors,
with and without Gaussian responses

Particle identification for STRAW/TOF/Aerogel

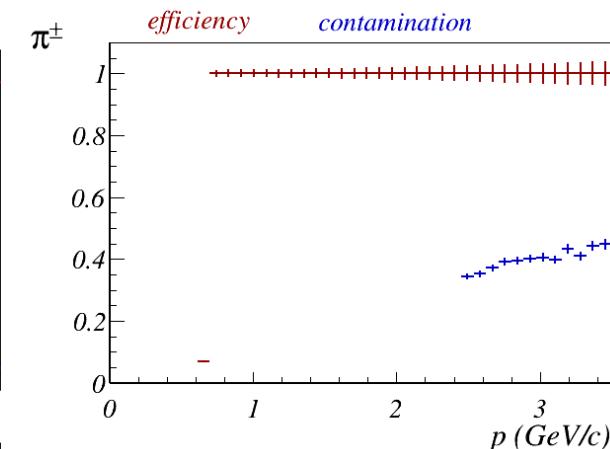
STRAW ($n\sigma < 2$)



TOF ($n\sigma < 3$)



Aerogel (yes/no)



$$\text{efficiency} = \frac{N_{corr}}{N_{true}}$$

$$\text{contamination} = \frac{N_{incorr}}{(N_{incorr} + N_{corr})}$$

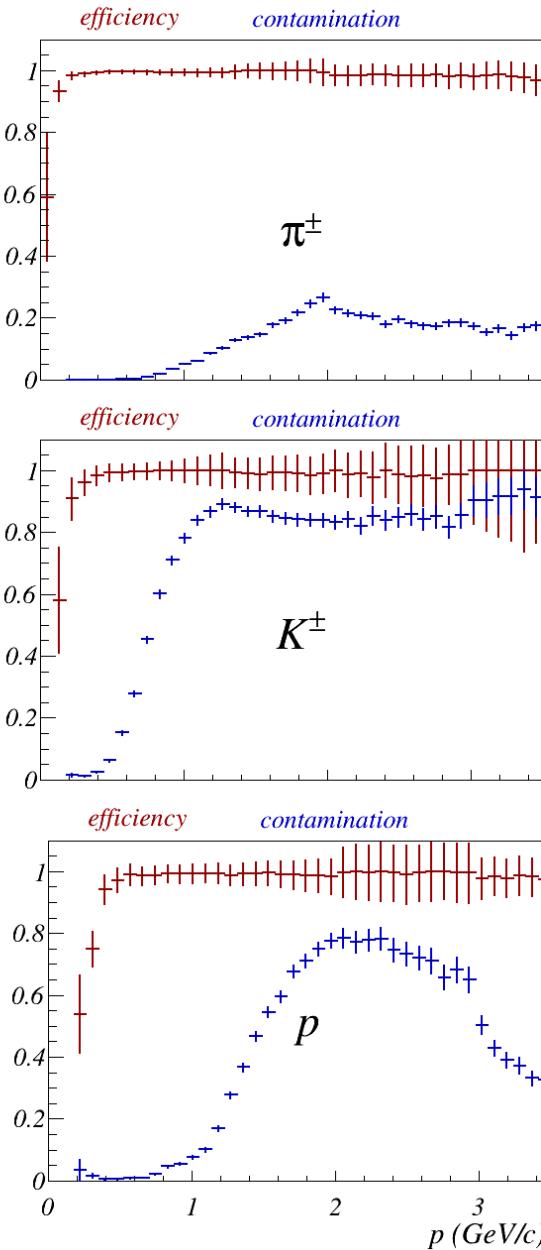
N_{corr} – the number of correctly identified particles of a certain type

N_{incorr} – number of misidentified particles a certain type

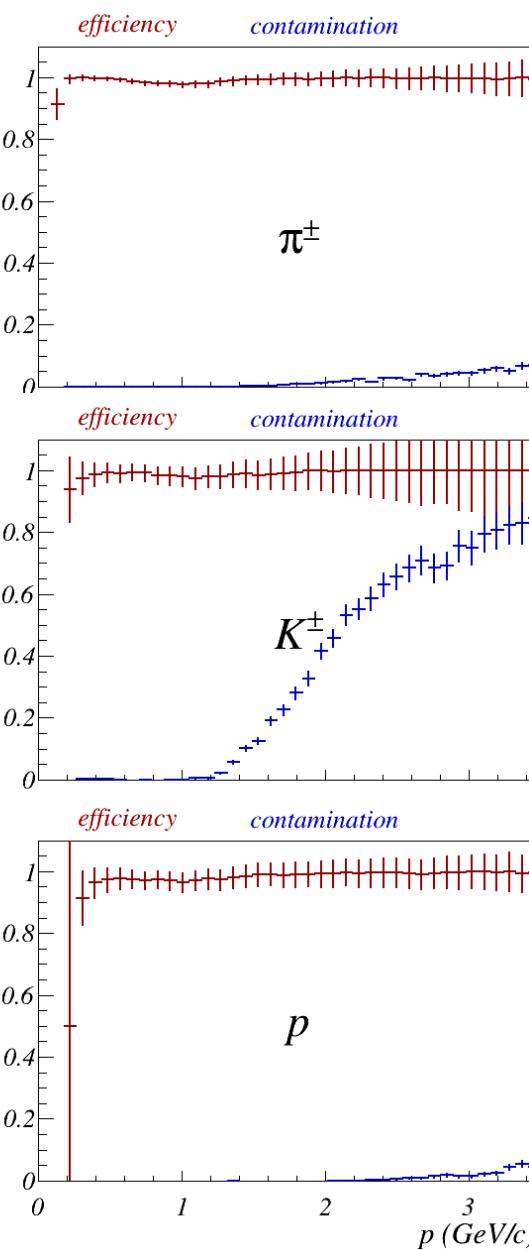
N_{true} – the true number of particles of a certain type .

Particle identification for STRAW and TOF

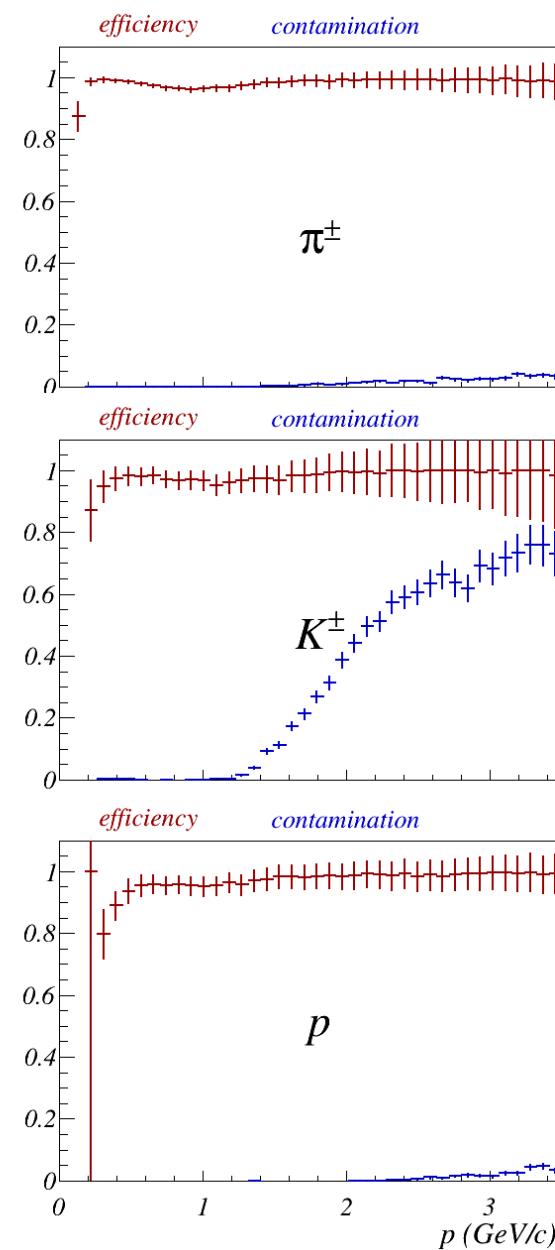
STRAW ($n\sigma < 2$)



TOF ($n\sigma < 3$)



TOF+STRAW ($n\sigma < 3$)



Bayes approach

S - a raw signal from a detector

$S(H_i)$ - expected average signal for a given species $H_i(\pi, K, p, \dots)$

The Bayes theorem

probability that the particle is of species H_i , given \vec{S}

$$P(H_i|\vec{S}) = \frac{P(\vec{S}|H_i)C(H_i)}{\sum_{k=\pi, K, p} P(\vec{S}|H_k)C(H_k)}$$

a posterior probability *A priori probability for H_i*

$$P(S|H_i) = \frac{1}{\sqrt{2\pi}\sigma} e^{\frac{-(S-S(H_i))^2}{2\sigma^2}}$$

One detector

The conditional probability that a particle of species H_i produces a signal S (in this case expressed with a Gaussian response)

$$P(\vec{S}|H_i) = \prod_{\alpha=TOF, STAW, \dots} P_\alpha(S_\alpha|H_i)$$

Many detectors

The conditional probability that a particle of species H_i produces the set of signals

What is priors

Strategy to calculate

Iterative procedure based on a set of unidentified tracks
(raw yield $Y(p)$)

1) Start with “flat” priors (i.e 1 for all species)

$$P(H_i|\vec{S}) = \frac{P(\vec{S}|H_i)C(H_i)}{\sum_{k=\pi, K, p} P(\vec{S}|H_k)C(H_k)}$$
$$P(m^2) = \frac{1}{\sqrt{2\pi}\sigma(p)} e^{-\frac{(m_{TOF}^2 - m_{fit}^2)^2}{2\cdot\sigma(p)^2}}$$

2) Bayesian posterior $P_n(H_i|S)$ at step n obtained from
unidentified raw yield

3) Obtain identified raw yields at step $n+1$ using posteriors as
weights

4) Obtain a new set of priors from the relative ratios of
identified spectra

Priors obtained as a function of p

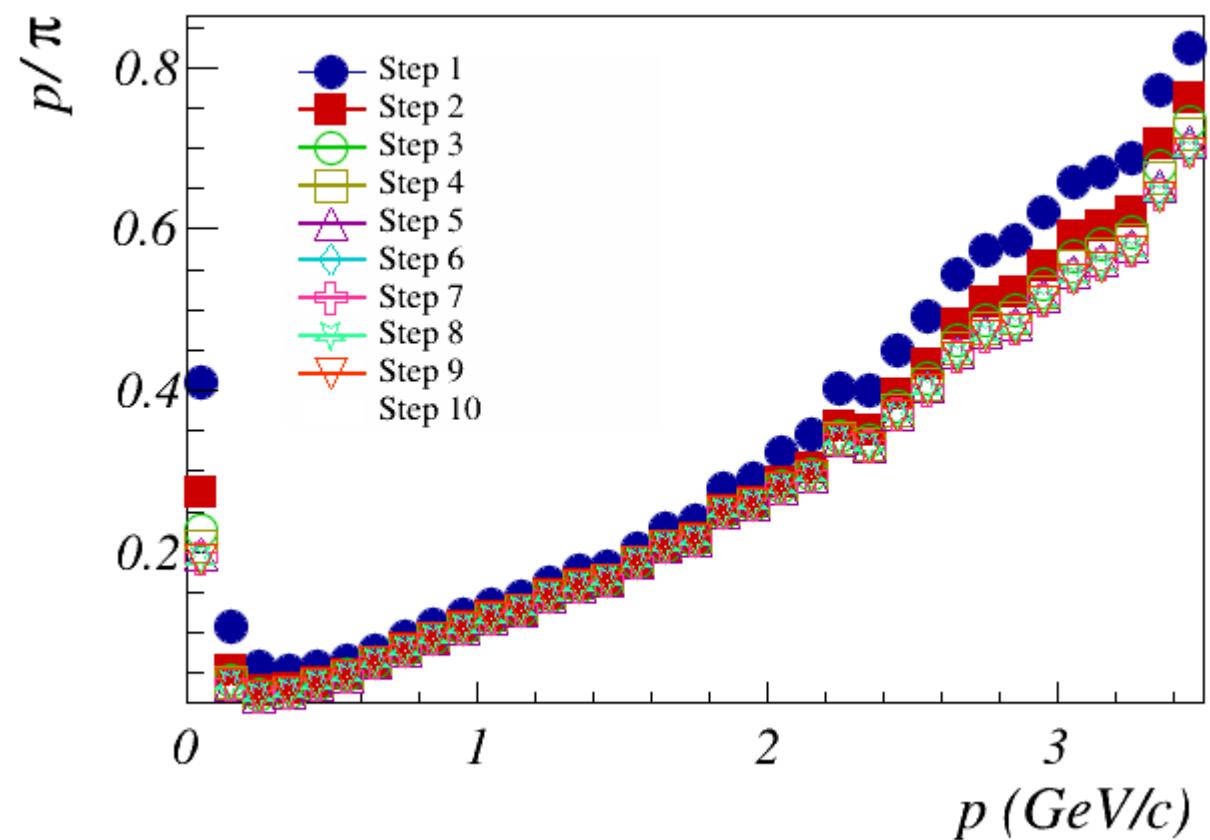
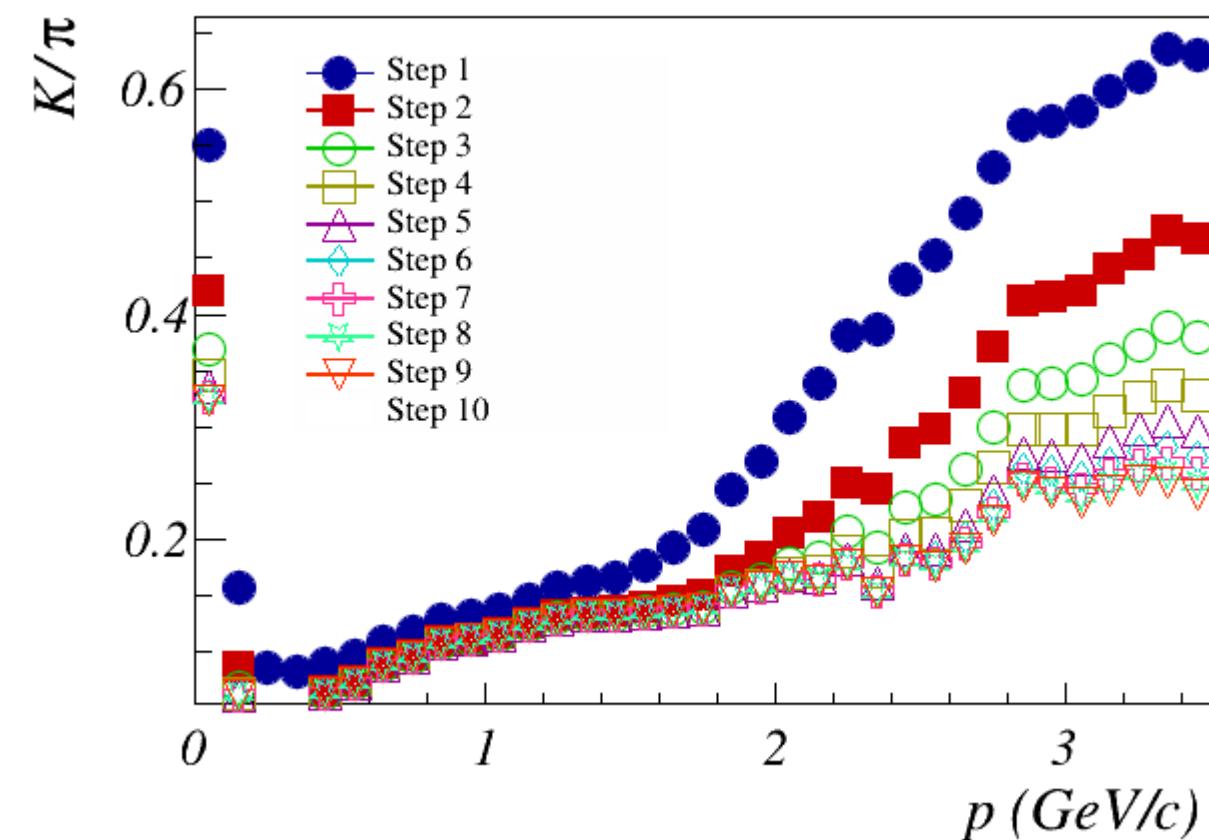
$$Y_{n+1}(H_i, p) = \sum_S P_n(H_i|S)$$

$$C_{n+1}(H_i, p) = \frac{Y_{n+1}(H_i, p)}{Y_{n+1}(H_\pi, p)}$$

Separate sets of priors have to be evaluated for each collision system p-p, d-d, p-d and energies

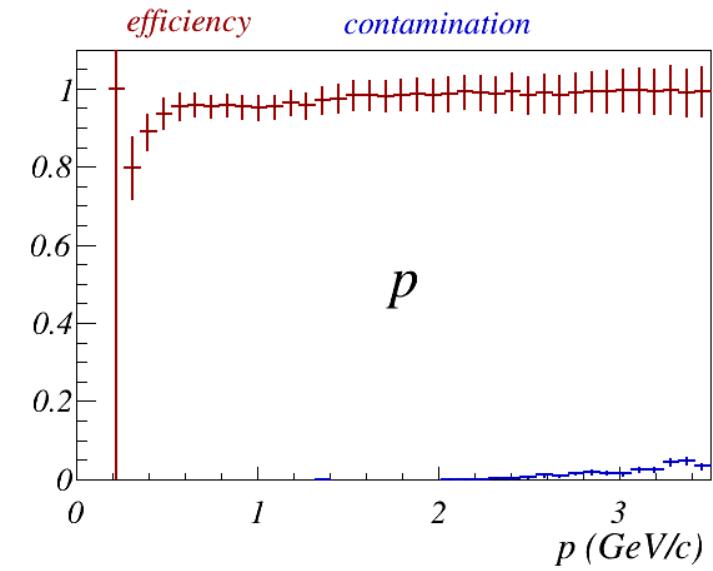
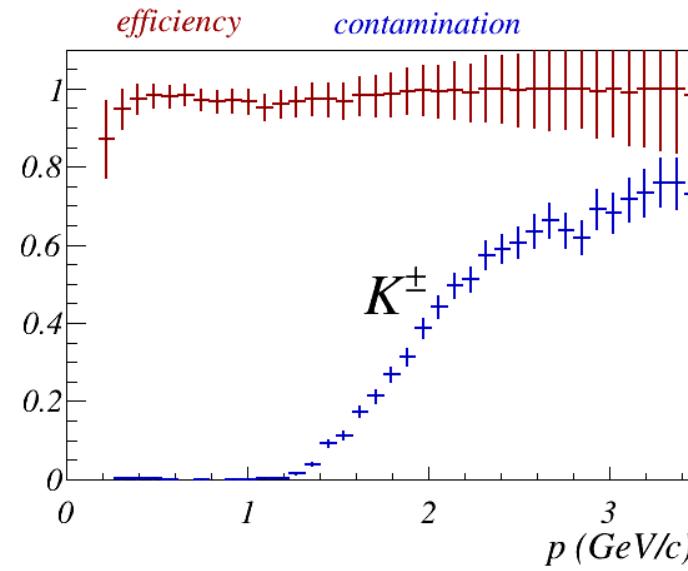
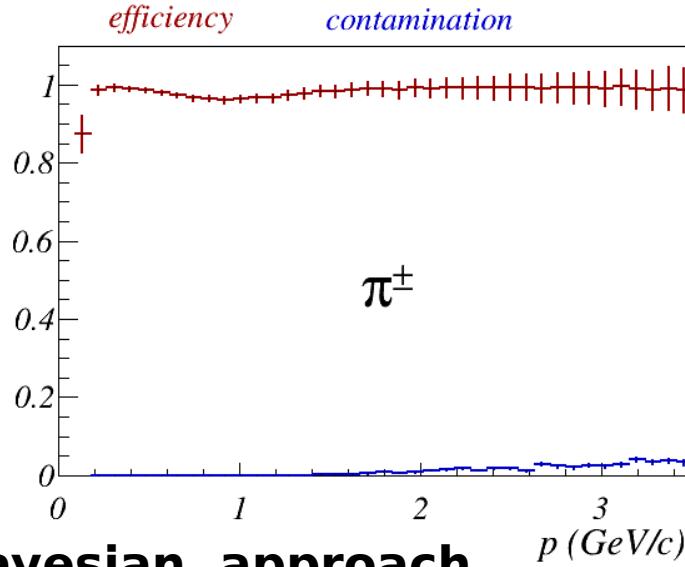
Calculation priors: TOF+STRAW

The extracted K/π and p/π ratio of the priors is shown as a function of p at each step of the iteration.



n -sigma and Bayesian approach for STRAW and TOF

n -sigma

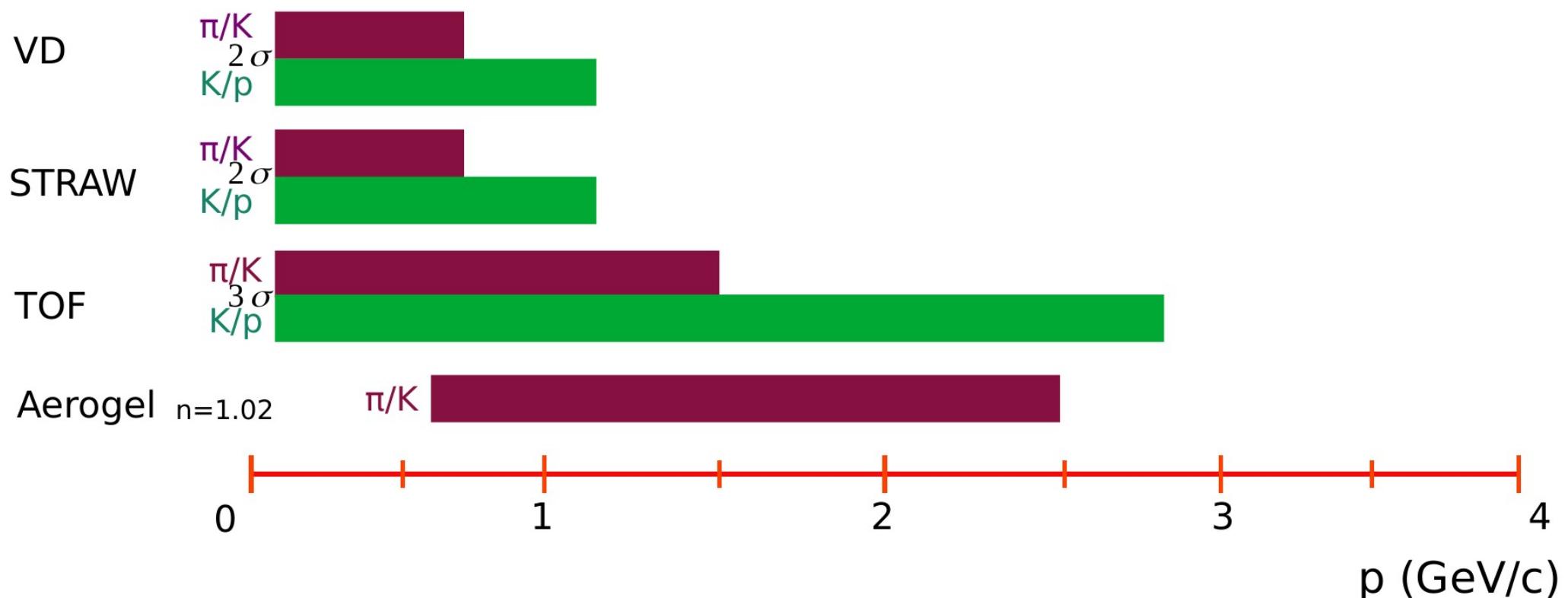


n -sigma: fixed cut

Bayesian: the selection on probability allows to maximize(minimize) efficiency(contamination)

Conclusion

- Methodology for particle identification in SPD for STRAW and TOF was developed, and the code is implemented in SpdRoot.



Thank you for your attention